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U.S. UTILITY Patent Application

PATENT NUMBER and
ISSUE DATE

APPL NUM 10054605	FILING DATE 11/13/2001	CLASS 257	SUBCLASS 626	GAU 2815	EXAMINER Brook
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Stamper Anthony;

****CONTINUING DATA VERIFIED:**
THIS APPLICATION IS A DIV OF 09/361,573 07/27/1999 PAT 6,342,733

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**** FOREIGN APPLICATIONS VERIFIED:**

PG-PUB <input type="checkbox"/> DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>
Foreign priority claimed <input type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO
35 USC 119 conditions met <input type="checkbox"/> yes <input type="checkbox"/> no	YOR919990336US2
Verified and Acknowledged Examiners's initials	
TITLE : Reduced electromigration and stressed induced migration of Cu wires by surface coating	
U.S. DEPT. OF COMM./PAT. & TM.-PTO-436L (Rev. 12-94)	

NOTICE OF ALLOWANCE MAILED		CLAIMS ALLOWED	
ISSUE FEE Amount Due Date Paid		Total Claims	Print Claim for O.G.
		DRAWING Sheet/Dwg. Figs. Drwg. Print Fig.	
<input type="checkbox"/> TERMINAL DISCLAIMER		Application Examiner	
		PREPARED FOR ISSUE	
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